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**PRODUCT / PROCESS CHANGE NOTIFICATION**  
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24-OCT-2000

**SUBJECT: Product/Process Change Notification 10340**

**TITLE: SEEFULL CHINA FAB/ASSY SITE QUAL FOR GEN. PURPOSE RECTIFIERS**

**EFFECTIVE DATE: 03-Feb-2001**

**AFFECTED CHANGE CATEGORY(S)**

SUBCONTRACTOR ASSEMBLY SITE  
SUBCONTRACTOR FAB SITE

**AFFECTED PRODUCT DIVISION(S)**

BIPOLAR DISCRETES PRODUCTS DIVISION

**ADDITIONAL RELIABILITY DATA: Available**

Contact (George Dorman, <R23125@onsemi.com>)

**SAMPLES: Available**

Contact (Mike Schager, <RMF150@onsemi.com>)

**FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:**

Contact (Mike Schager, <RMF150@onsemi.com>)

**DISCLAIMER:**

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor sales office.

**DESCRIPTION AND PURPOSE:**

ON Semiconductor is pleased to announce that it has qualified our Subcontractor Lite-On's Seefull China facility for the Wafer Fab and Assembly of General Purpose Axial-Lead products; 1N4001-series, 1N4933-series, 1N5400-series, and MR852-series.

Lite-On has been a subcontractor to ON Semiconductor for over 10 (ten) years and is certified to QS-9000, ISO-9001, and ISO-14000. There will be no change to the function of the devices. Device parameters will continue to meet all Data Book specifications, and reliability will continue to meet or exceed ON Semiconductor standards.



**QUALIFICATION PLAN: (PER AEC-Q101 GUIDELINES)**

<b>TEST*</b>	<b>CONDITIONS</b>	<b>EXCEPTIONS</b>
HTRB	Vr=80% rated, Ta=150 degC , 1000 hrs.	
Temp Cycle	Air to Air, -65 to +150 degC, 1000 cycles	
Autoclave	Ta=121 degC, RH= 100%, PSIg=15, 96 hrs.	
H3TRB	Vr=80% rated, Ta=85 degC, RH= 85%, 1000 hrs.	
IOL	Ta=25 degC, delta Tj =>100 degC, 2 minutes on/off, 15000 cycles	
High Temp Storage	150 degC, 1000 hrs.	
D.P.A.	Post H3TRB and Temp Cycle	
Physical Dimension	Per Case Outline Drawing	
Terminal Strength	Force reqd to separate solder joints	Lead Pull
Res. to Solvents	Verify Marking Permanency	
Res. To Solder Heat	270 degC, Td=10s	
Solderability	245 degC Td= 5s	
Thermal Resistance	Measure Rjc	

**QUALIFICATION VEHICLE JUSTIFICATION**

<b>FAMILY</b>	<b>Io</b>	<b>QUAL. DEVICE</b>	<b>REASON CHOSEN</b>
Standard Recovery	3A	1N5408	Largest Die/Highest Voltage
	1A	1N4007	Largest Die/Highest Voltage
Fast Recovery	3A	MR856	Largest Die/Highest Voltage
	1A	1N4937	Largest Die/Highest Voltage



**RELIABILITY DATA SUMMARY**

(INTERIM RELIABILITY TESTS)

**RESULTS: STANDARD RECOVERY PRODUCTS**

TEST DESCRIP.	INTERVAL	1N5408		1N4007		TEST LOT PK51495732
		CONTROL ZP05957832	TEST LOT PK60387832	CONTROL ZP05895732	TEST LOT PK60115732	
HTRB	500 hrs	0/77	0/77	0/77	0/77	0/77
Temp Cycle	500 cyc	0/77	0/77	0/77	0/77	0/77
Autoclave	96 hrs	0/77	0/77	0/77	0/77	0/77
H3TRB	500 hrs	0/77	0/77	0/77	0/77	0/77
IOL	7500 cyc	0/77	0/77	0/77	0/77	0/77
High Temp.	500 hrs	0/77	0/77	0/77	0/77	0/77
Storage						
D.P.A.	-	1Nov00	1Nov00	1Nov00	1Nov00	1Nov00
Phys. Dimen.	-	Pass	Pass	Pass	Pass	Pass
Terminal Strength	-	Pass	Pass	Pass	Pass	Pass
Resist. to Solvents	-	Pass	Pass	Pass	Pass	Pass
Res. To Solder Heat	-	Pass	Pass	Pass	Pass	Pass
Solderability-Thermal Resistance	-	Pass 1Nov00	Pass 1Nov00	Pass 1Nov00	Pass 1Nov00	Pass 1Nov00

**RESULTS: FAST RECOVERY PRODUCTS**

TEST DESCRIP.	INTERVAL	MR856		1N4937		
		CONTROL ZP06508632	TEST LOT PK90368632	TEST LOT PK90398632	CONTROL ZP06436732	TEST LOT PK60036732
HTRB	500 hrs	0/77	0/77	0/77	0/77	0/77
Temp Cycle	500 cyc	0/77	0/77	0/77	0/77	0/77
Autoclave	96 hrs	0/77	0/77	0/77	0/77	0/77
H3TRB	500 hrs	0/77	0/77	0/77	0/77	0/77
IOL	7500 cyc	0/77	0/77	0/77	0/77	0/77
High Temp.	500 hrs	0/77	0/77	0/77	0/77	0/77
Storage						
D.P.A.	-	1Nov00	1Nov00	1Nov00	1Nov00	1Nov00
Physical Dimension	-	Pass	Pass	Pass	Pass	Pass
Terminal Strength	-	Pass	Pass	Pass	Pass	Pass
Resist. to Solvents	-	Pass	Pass	Pass	Pass	Pass
Res. to Solder Heat	-	Pass	Pass	Pass	Pass	Pass
Solderability-Thermal Resistance	-	Pass 1Nov00	Pass 1Nov00	Pass 1Nov00	Pass 1Nov00	Pass 1Nov00

**Reliability Testing Conclusions:**

Interim Reliability Test data is consistent with passing ON Semiconductor / AEC-Q101 requirements. A copy of the full Reliability Report will available in November 2000, upon request.



**ELECTRICAL CHARACTERIZATION RESULTS:**

**STANDARD RECOVERY PRODUCTS Tj = 25 degC**

DEVICE NUMBER	1N5408		1N4007		
GROUP	CONTROL	TEST LOT	CONTROL	TEST LOT	TEST LOT
LOT NUMBER	ZP05957832	PK60387832	ZP05895732	PK60115732	PK51495732
Vf (mV)					
Minimum	921	882	899	897	903
Maximum	941	905	929	927	953
Average	929	891	912	911	925
Std. Dev.	4	4	6	6	10
Cpk	5.9	9.1	4.9	4.9	2.5
Ir @ 1000V (uA)					
Minimum	0.147	0.158	0.105	0.103	0.047
Maximum	0.465	0.448	0.210	0.208	0.343
Average	0.308	0.269	0.138	0.136	0.111
Std. Dev.	0.040	0.060	0.021	0.021	0.052
Cpk	80.8	54.1	77.2	77.2	31.3

**FAST RECOVERY PRODUCTS Tj = 25 degC**

DEVICE NUMBER	MR856		1N4937		
GROUP	CONTROL	TEST LOT	TEST LOT	CONTROL	TEST LOT
LOT NUMBER	ZP06508632	PK90368632	PK90398632	ZP06436732	PK60036732
Vf (mV)					
Minimum	958	974	961	972	1005
Maximum	1102	1171	1187	1176	1156
Average	1016	1037	1048	1054	1052
Std. Dev.	30	38	45	41	25
Cpk	2.6	1.9	1.5	1.2	2.0
Ir @ 600V					
Minimum	0.515	0.110	0.079	0.183	0.172
Maximum	1.170	1.197	1.282	0.708	0.519
Average	0.763	0.765	0.623	0.315	0.270
Std. Dev.	0.147	0.240	0.369	0.103	0.063
Cpk	20.9	12.8	8.5	15.2	25.0
Trr (nS)					
Minimum	82	73	69	73	72
Maximum	98	105	97	94	107
Average	91	84	83	83	84
Std. Dev.	4.4	5.2	7.1	4.3	6.1
Cpk	8.3	7.4	5.5	9.2	6.4

**CHANGED PART IDENTIFICATION:**

Customers may receive these products manufactured at the Seefull, China site starting with Date Code 0105 or later. The marking on these products will include PK.



**AFFECTED DEVICE LIST:**

**PART Number**

1N4001  
1N4001FF  
1N4001RL  
1N4002  
1N4002FF  
1N4002RL  
1N4003  
1N4003FF  
1N4003RL  
1N4004  
1N4004FF  
1N4004RL  
1N4005  
1N4005FF  
1N4005RL  
1N4006  
1N4006FF  
1N4006RL  
1N4007  
1N4007FF  
1N4007RL  
1N4933  
1N4933RL  
1N4934  
1N4934RL  
1N4935  
1N4935RL  
1N4936  
1N4936RL  
1N4937  
1N4937RL  
1N5400  
1N5400RL  
1N5401  
1N5401RL  
1N5402  
1N5402RL  
1N5404  
1N5404RL  
1N5406  
1N5406RL  
1N5407  
1N5407RL  
1N5408  
1N5408RL  
MR850  
MR851  
MR851RL  
MR852  
MR852RL  
MR854  
MR854RL  
MR856  
MR856RL